

 <p>LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)</p>	ATTY. DOCKET NO. 9301-159	APPLICATION NO. 10/520,031
	APPLICANT Marton <i>et al.</i>	
	FILING DATE June 27, 2003	ART UNIT 1637

U.S. PATENT DOCUMENTS

*Examiner Initials	Document Number	Date mm/dd/yy	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear

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/YK/	C29 Supplementary European search report dated May 16, 2007 for European Patent Application No. 03 762 218.0 - 1222.	

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EXAMINER /Young J. Kim/	DATE CONSIDERED 02/03/2009
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